



Express Mail Label No.

Dated: _____

Docket No.: 06920/000J924-US0
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Hiroshi Koshiba

Application No.: 09/975,835

Confirmation No.: 2278

Filed: October 11, 2001

Art Unit: 2133

For: SEMICONDUCTOR TEST APPARATUS AND
CONTROL METHOD THEREFOR

Examiner: J. P. Trimmings

AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)

MS AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INTRODUCTORY COMMENTS

In response to the Office Action dated December 3, 2004 (Paper No. 11232004), and subject to the approval of the Examiner, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Amendments to the Drawings begin on page 6 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 7 of this paper.

An **Appendix** including amended drawing figures is attached following page 10 of this paper.